

Bias Voltage Dependence of the MIP Peak Position

Rikkyo Hayato Yanagawa

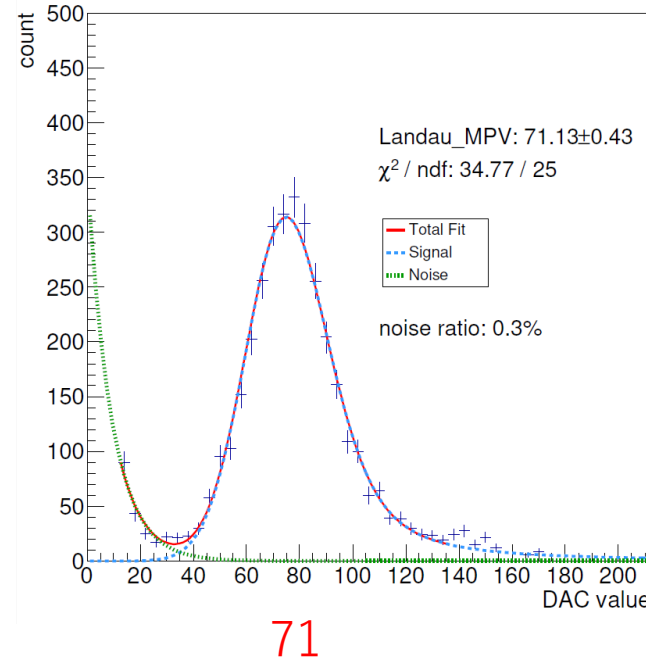
My Diploma thesis

Bias voltage dependence of the MIP peak position

Motivation

- The MIP peak appeared around ADC=71 in the 3rd beam test with bias voltage=50V.
- While in Run24 pp collisions, it was 100V.
- Although the beam type and energy differed, both are considered almost MIP.
- The MIP peak positions appeared 30% difference between two measurements.
- The study is to check the Bias voltage dependence of the MIP peak position.

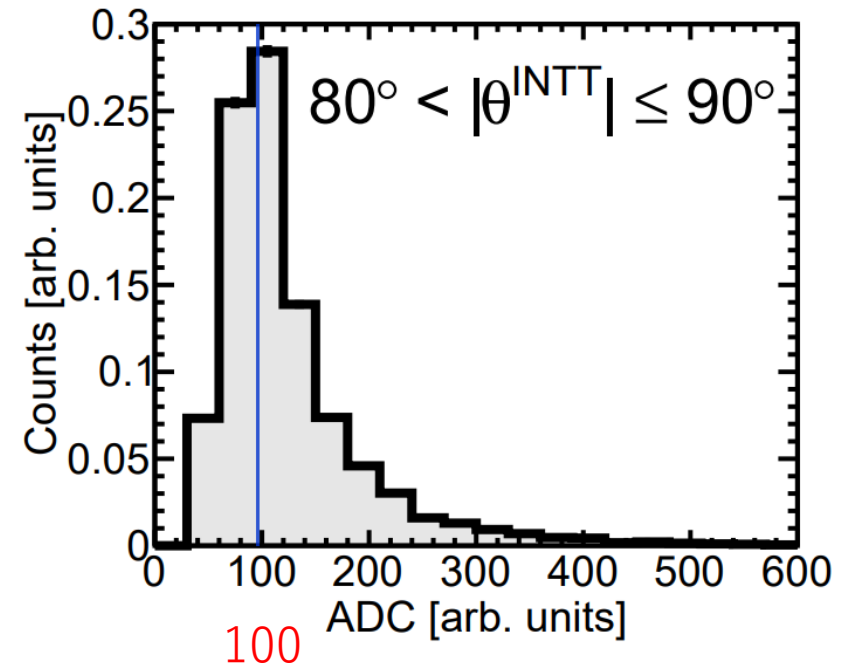
Testbeam2021, 50 V
Positron beam, 1 GeV



Analysis by Sugiyama(NWU)

(NWU)杉山由佳,202402,RHIC-sPHENIX 実験の初年度のデータを用いた中間飛跡検出器INTTの動作検証より

sPHENIX Preliminary Run-24, 100 V
Proton-Proton collision at 200 GeV



https://www.sphenix.bnl.gov/sites/default/files/2024-10/sphenix-perf-9-24-mip_50889_multi_panel_preliminary.pdf

Run with various bias voltage

- Bias voltage scan was conducted in Run24 Au+Au collision.
- A pair of special runs were taken for bias voltages at 50V, 75V, 100V.

Date/Time	Run#	Run Type	Mag	Bias voltage				
2024/10/16 1:11	54679	beam	on	50V				
2024/10/16 1:41	54681	beam	on	75V				
2024/10/16 2:05	54685	beam	on	100V				
2024/10/16 2:19	54686	beam	on	50V				
2024/10/16 2:30	54687	beam	on	75V				
2024/10/16 2:46	54688	beam	on	100V				
ADC	0	1	2	3	4	5	6	7
DAC	35-45	45-60	60-90	90-120	120-150	150-180	180-210	210-

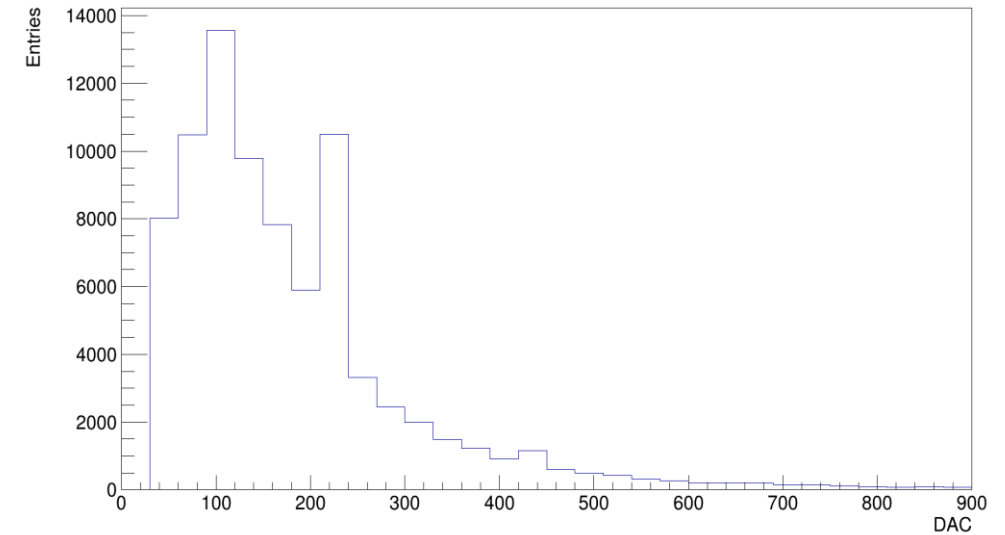
Details of data

ADC	0	1	2	3	4	5	6	7
DAC	35-45	45-60	60-90	90-120	120-150	150-180	180-210	210-

Run#	Run Type	Mag	Link	Duration (min)	Event	MBD-NS	Active Felix List	DAC 0	L1 Delay	n_coll	open time	Modebit	Comments
54688	beam	On		10min			All Felix	35	114	100	60	intt_triggermode	HV scan HV=100V

- The run described slide 3 were processed as follows
(The initial process with Fun4All were handled by Genki)
 - Excluding hot channel by the hot channel of Run 50377.
 - Clustering was done.
 - 10k events were analyzed.
 - Vertex was reconstructed by using InttXYVertexFinder and InttZVertexFinder in the coresoftware repository.
- Note** : The run was taken in the local mode so MBD data is not available.
- The cluster ADC histogram was filled from 0 to 900 and was divided into 30 bins.

ADC_distribution



To do

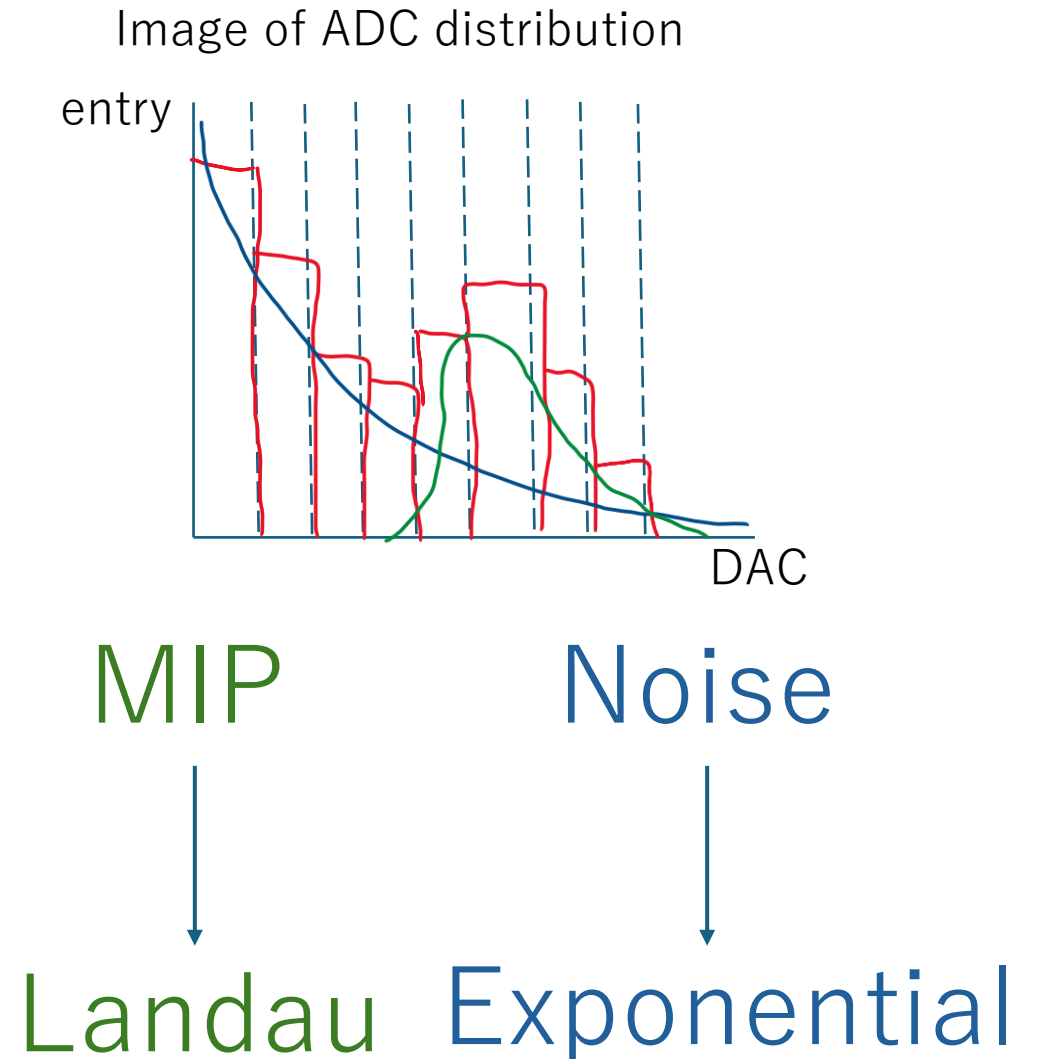
- Modification for peaks at DAC=210(ADC7)
- Compare MIP peaks across different bias voltages

Determination of the MIP position by fitting

- The ADC distribution assumed to have MIP and noise components.
- So I use the following function. A sum of **Landau** distribution and an **exponential** function.

$$f(x) = \underline{A_1} \cdot \text{Landau}(x, \underline{MPV}, \underline{\sigma}) + \underline{A_2} \cdot e^{-\frac{x}{\underline{\tau}}}$$

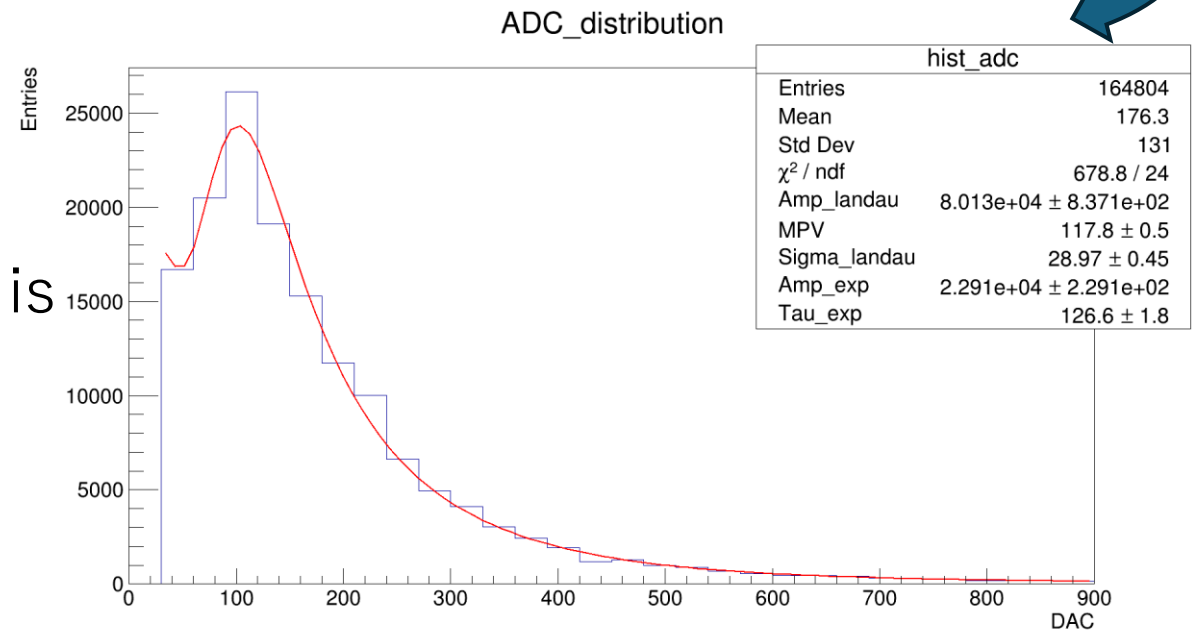
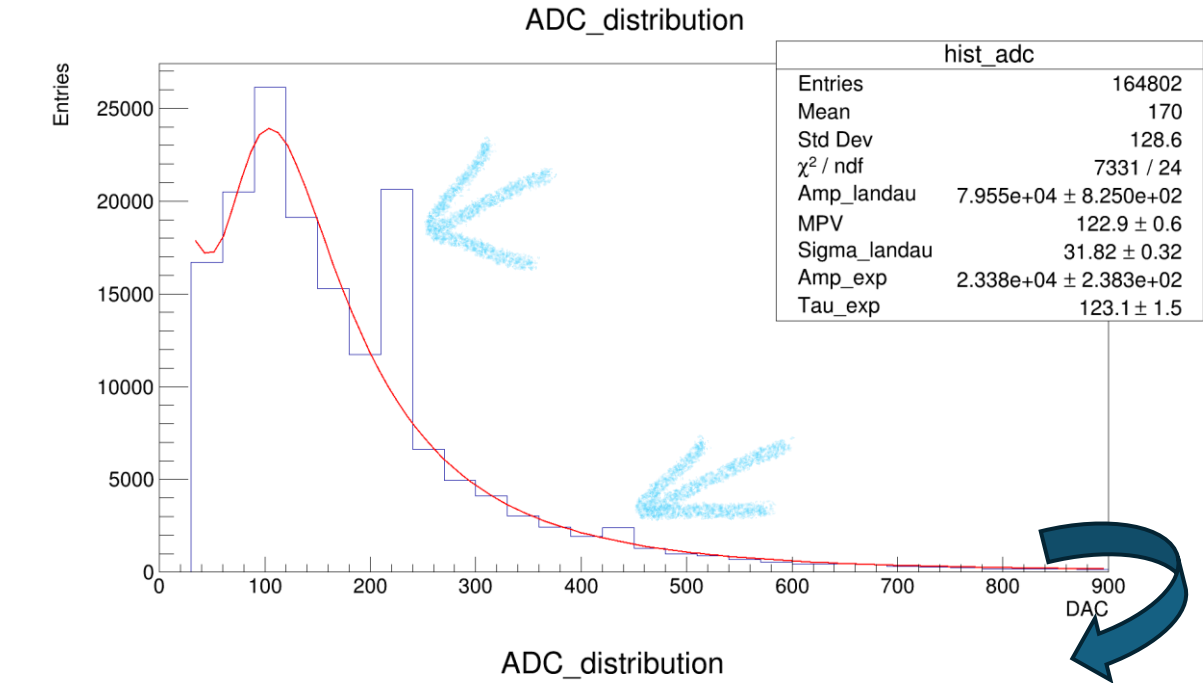
Note : I decide these parameter by fitting.



ADC7peak cut

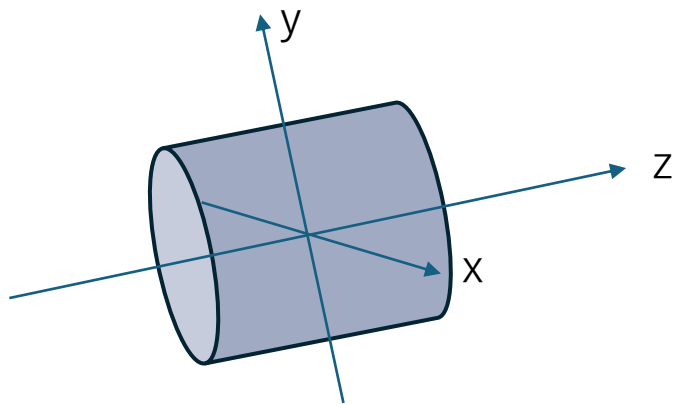
- Due to the FPHX chip's specification, hits with DAC value 210 or more are assigned to 210. So I cut two-thirds of single-hit clusters.
→ See the reference for more details
([1] M.Hata, 2024. [2] G.Nukazuka, 2024).

- Process DAC value 420 (cut 8/9 double-hit clusters) same as 210.
- Better handling of the ADC overflow bin is under consideration.

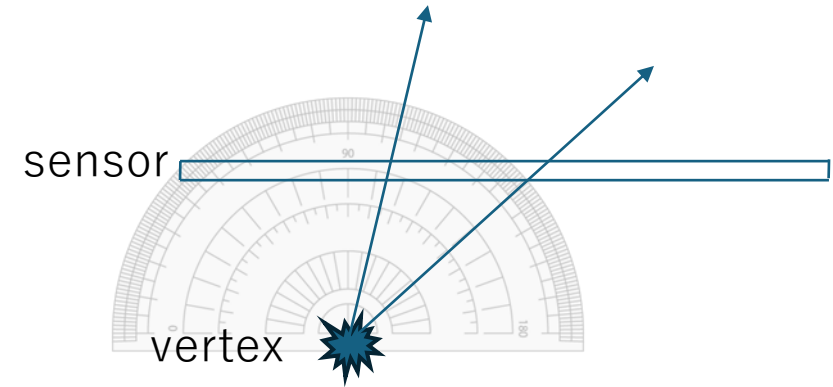


ADC distribution with theta

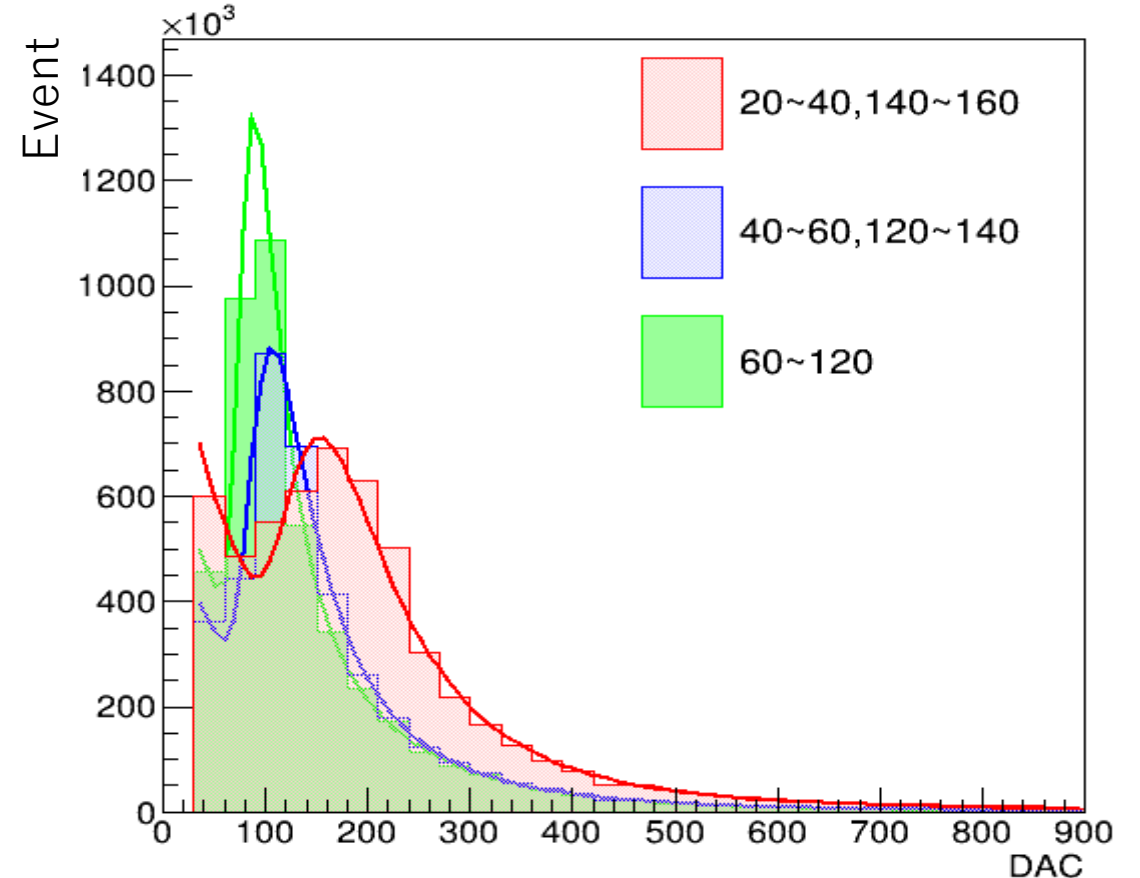
- Theta is polar angle of cluster in polar coordinate
- The MIP peak position moves to higher as lower theta region is selected.
- In this analysis, angular range is limited to simplify the case.



\vec{z} : beam direction
 \vec{y} : vertical direction
 $\vec{x} \equiv \vec{y} \times \vec{z}$.
 θ, ϕ : polar coordinate polar
and azimuthal angles

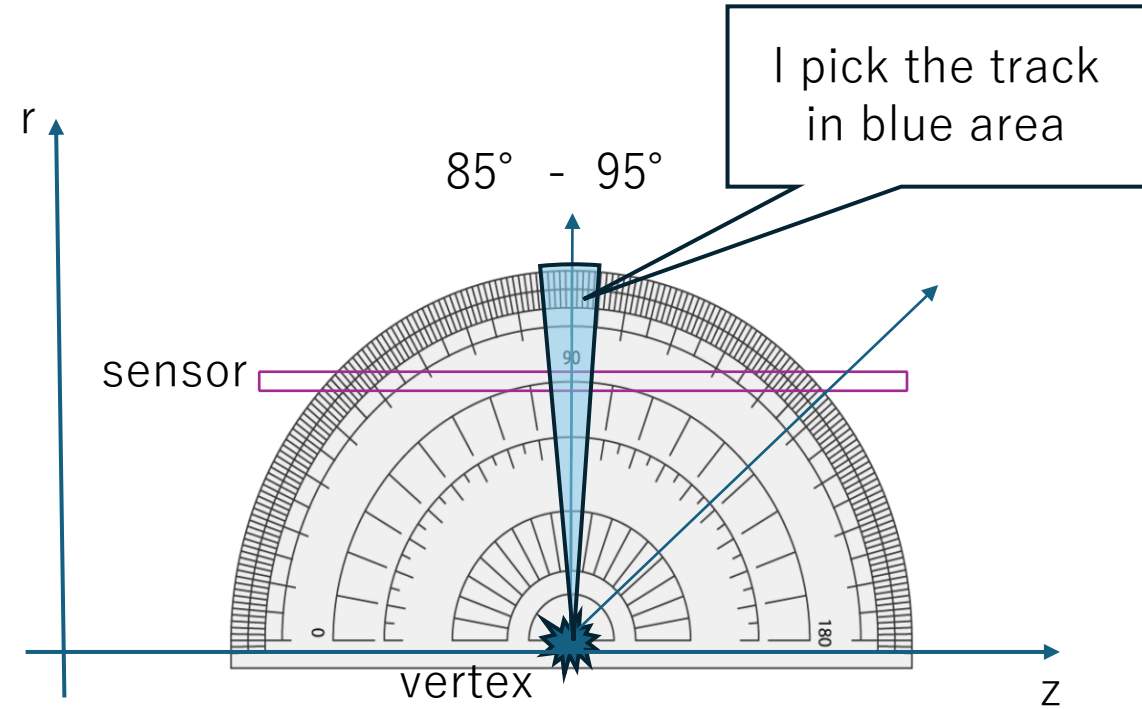
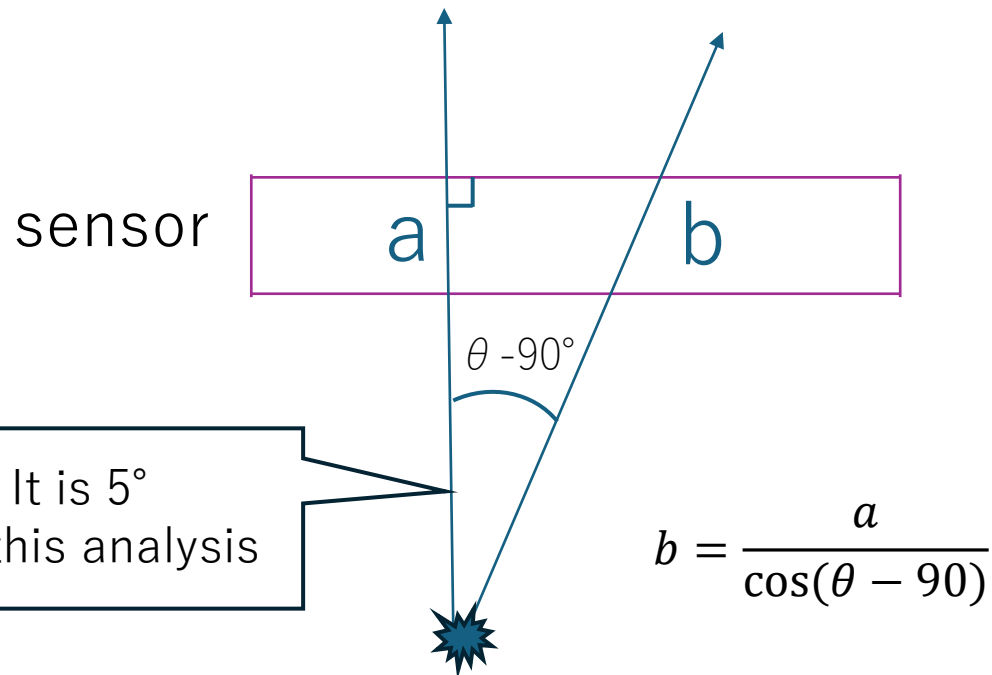


ADC_distribution



θ range selection

- Examining the cluster made by the track incident in vertical.
- θ region of $90^\circ \pm 5^\circ$ was selected for analysis.
- MIP peak position will have fluctuation up to 0.4%

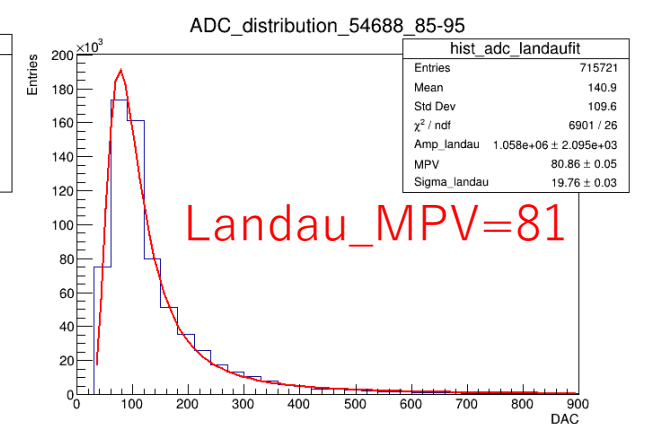
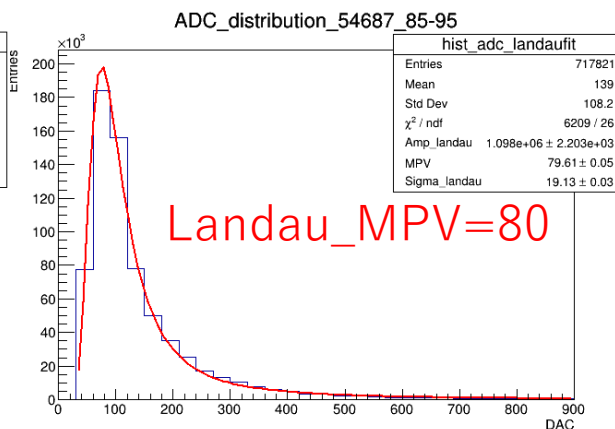
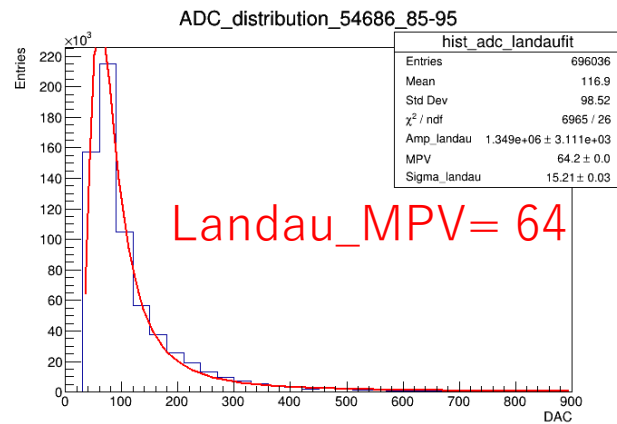
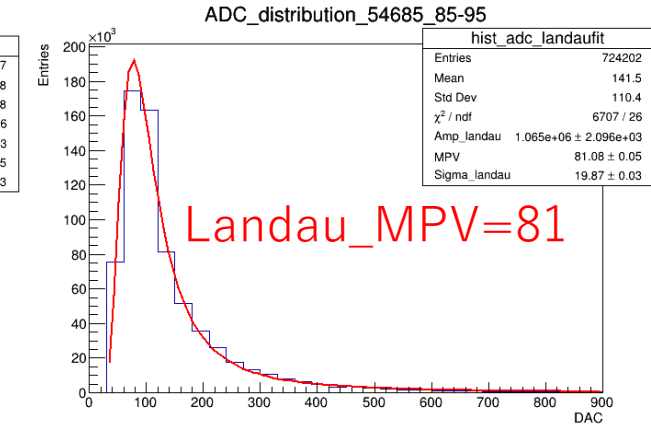
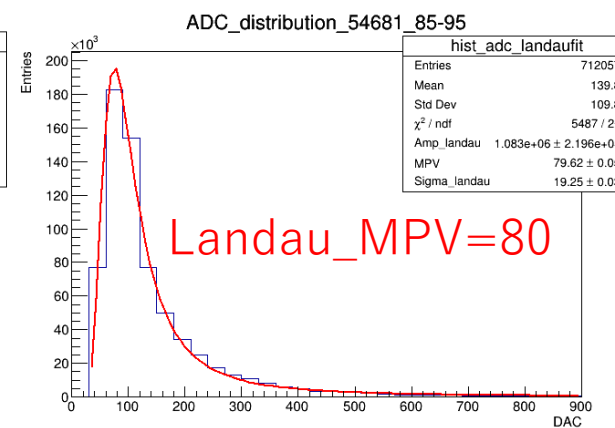
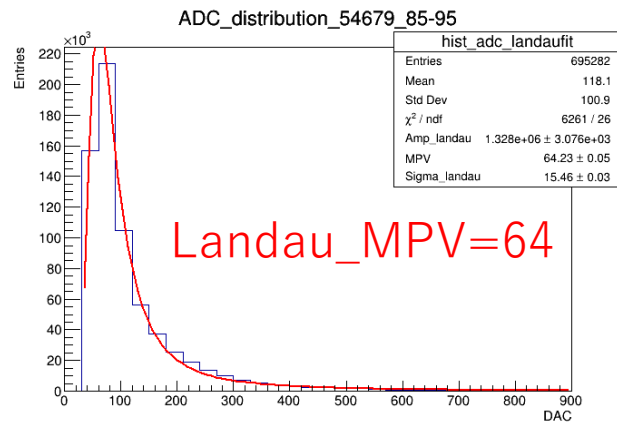


MIP peak each bias voltage

- Fitting with only **landau** for each bias voltage.
- Cluster ADC distribution for each run is shown with their fitting line.
- The red number written in the graph is MPV with no error.

Bias Voltage	50V	75V	100V
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- MIP peak position are different by each bias.
- Peak position especially depend on the first bin at 75V and 100V
- Chi square is too big(about 6000).

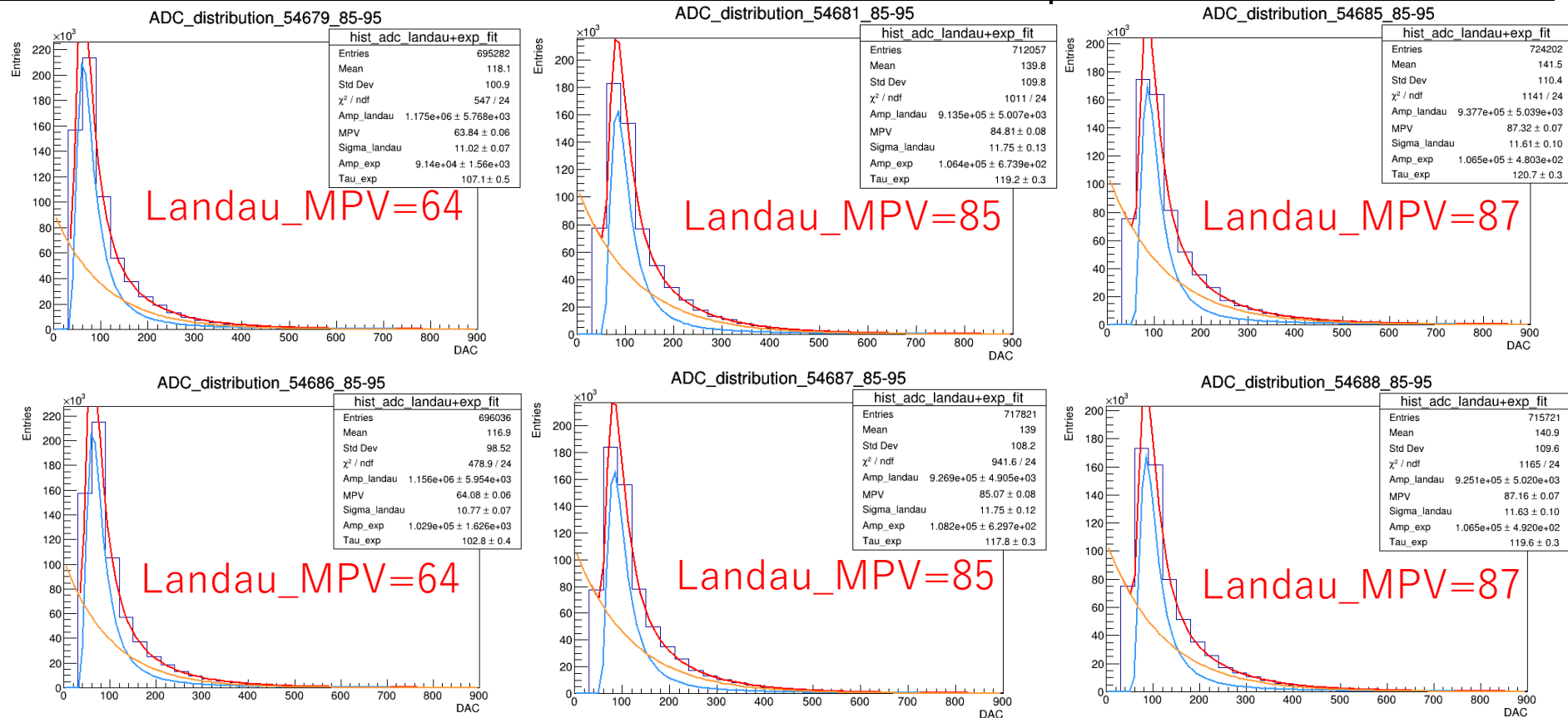


MIP peak each bias voltage

- Fitting with sum of **landau** distribution and an **exponential** function for each bias voltage.
- Cluster ADC distribution for each run is shown with their fitting line.
(sum of two functions → red, landau → blue, exponential → orange)

Bias Voltage	50V	75V	100V
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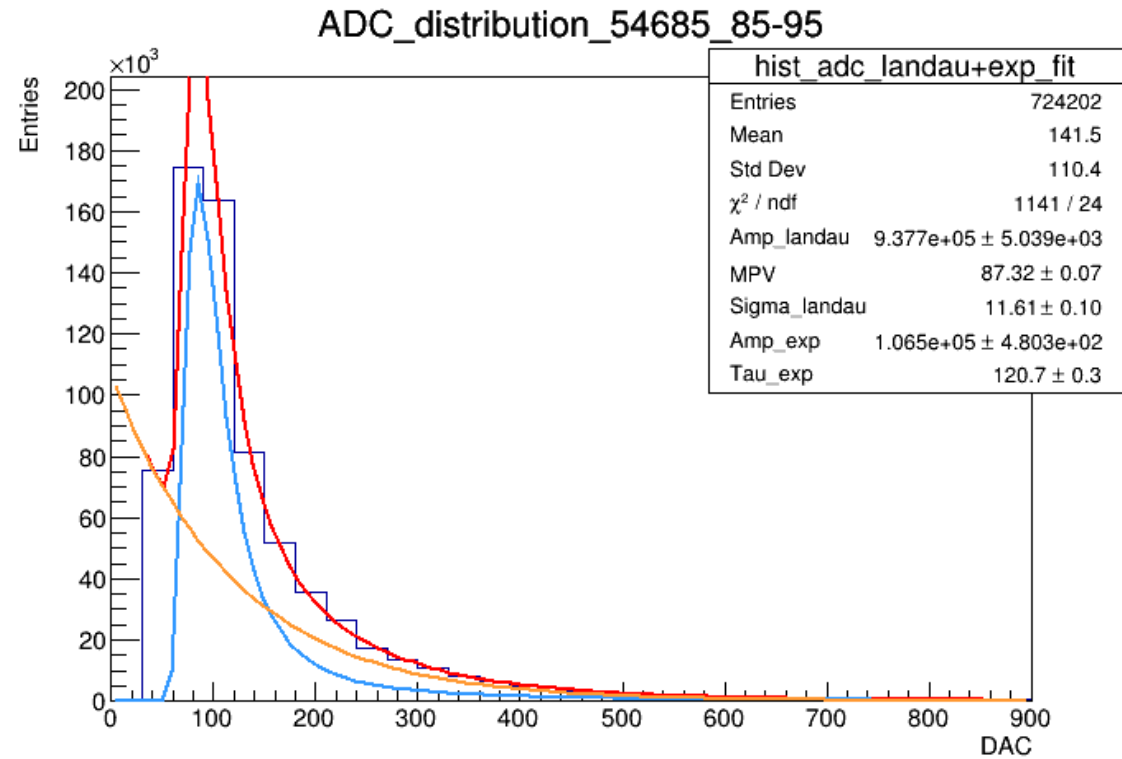
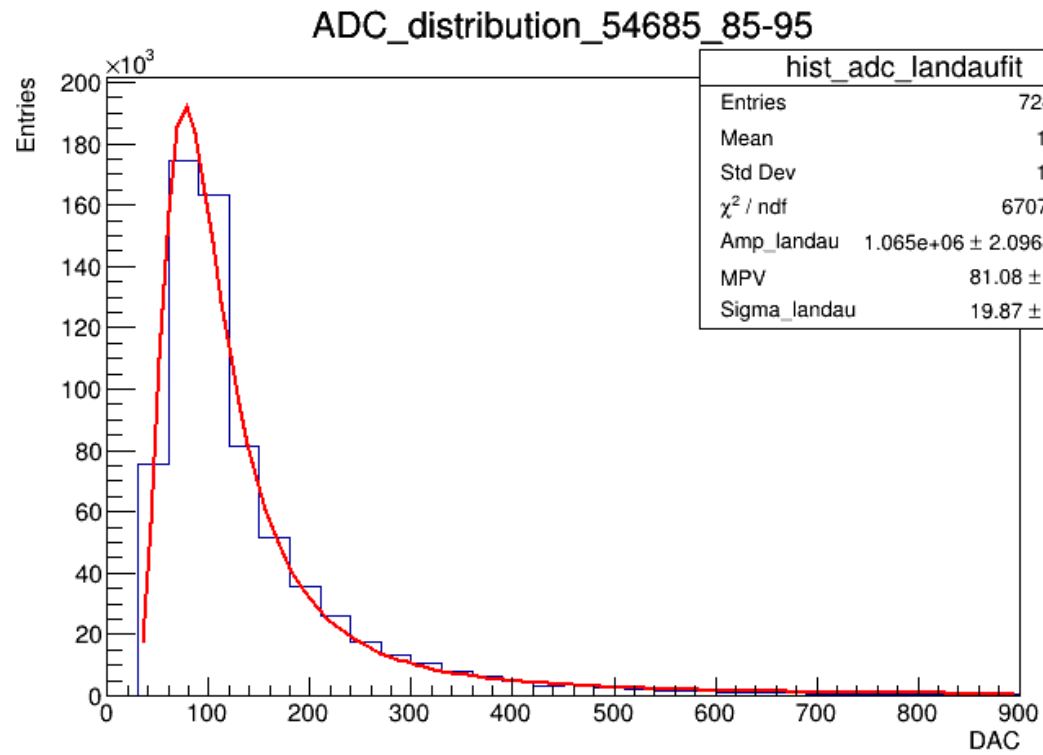
- MIP peak position are also different by each bias.
- Chi square is smaller than only landau fitting.



conclusion and next

- The fitting result at 50V seems to be consistent with 3rd beam test though, further check will be made as below.
- Better estimate of the noise component using shallower angle data samples.
- Check some fitting functions(convolution of landau and gaussian etc...).
- Improve the process of ADC7 handling.

Back up



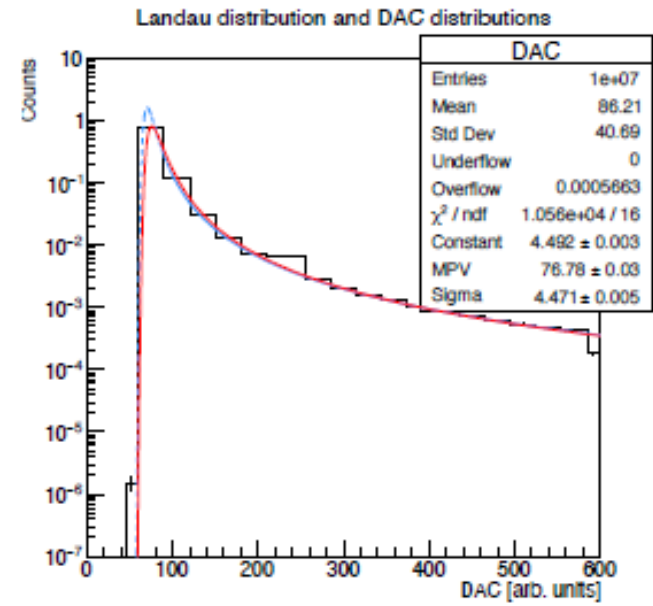
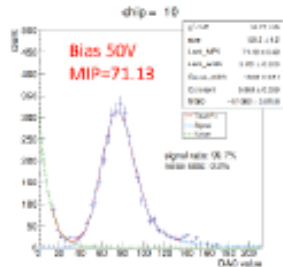
Back up

The modification factor for hits with ADC7

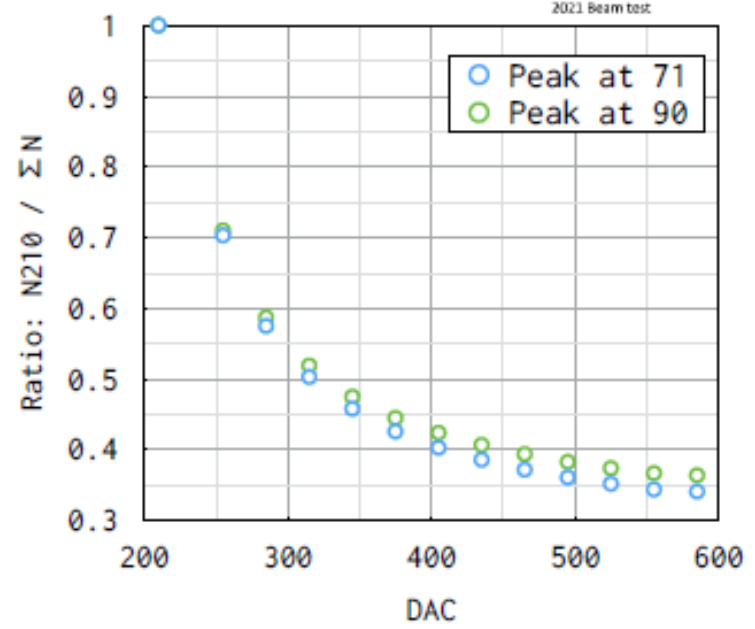
Parameters of landau distribution were taken from Yuka's study of DAC scan in the test beam experiment:

- MPV: 71.13
- width: 3.251

Note: The peak position is expected to at DAC 90



ADC	DAC	Value	Ratio
9	210	0.00651	100%
10	255	0.00276	70.3%
11	285	0.00206	57.5%
12	315	0.00162	50.3%
13	345	0.00127	45.8%
14	375	0.00105	42.6%
15	405	0.000869	40.3%
16	435	0.000726	38.6%
17	465	0.000632	37.2%
18	495	0.00054	36.1%
19	525	0.000472	35.2%
20	555	0.000421	34.4%
21	585	0.000181	34.1%



0.35 is reasonable for the modification factor

Back up

